


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,489	CHANG ET AL.	
	Examiner	Art Unit	
	Y. J. Han	2838	

SEARCHED			
Class	Subclass	Date	Examiner
323	312		
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327	530		
	534		
	535	12/05	gA

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR